

<p style="text-align: center;">JUN 3 0 2003</p> <p style="text-align: center;">U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</p> <p style="text-align: center;">JOINT OR PART CITED BY APPLICANT (Use separate sheet if necessary)</p>				ATTY. DOCKET NO. M122-1544		SERIAL NO.		
				APPLICANT Guy T. Blalock et al.				
				FILING DATE Filed herewith		GROUP 1765 (priority)		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
LV	AA	5,879,575	3/99	Tepman et al.				
	AB	5,868,853	2/99	Chen et al.				
	AC	5,830,279	11/98	Hackenberg				
	AD	5,817,578	10/98	Ogawa				
	AE	5,788,869	8/98	Dalton et al.				
	AF	5,756,400	5/98	Ye et al.				
	AG	5,681,424	10/97	Saito et al.				
	AH	5,679,215	10/97	Barnes et al.				
	AI	5,644,153	7/97	Keller				
	AJ	5,626,775	5/97	Roberts et al.				
	AK	5,468,686	11/95	Kawamoto				
LV	AL	5,780,338	7/98	Jeng et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
	AM						Yes	No
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
LV	AR		Stanley Wolf and Richard Tauber, Silicon Processing for the VLSI Era, Vol. 1, pp 549, 1986. <i>Copy enclosed</i>					
	AS							
	AT							
EXAMINER LAN VINH				DATE CONSIDERED 3/14/2003				
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								

Form PTO-149 O P I E JUN 30 2003 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT several sheets if necessary DEC 30 2002 O P I E P A T E N T & T R A D E M A R K O F F I C E		ATTY. DOCKET NO. MI22-1544	SERIAL NO.
		APPLICANT Guy T. Blalock et al.	
		FILING DATE Filed herewith	GROUP 1765 (priority)

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
LV	AA	4,513,021	4/85	Purdes et al.			
	AB	5,373,948	2/99	Kim			
	AC	5,843,239	12/98	Shrotriya			
	AD	5,716,494	2/98	Imai et al.			
	AE	5,593,540	1/97	Tomita et al.			
	AF	5,514,247	5/96	Shan et al.			
LV	AG	5,242,538	9/93	Hamrah et al.			
	AH	5,681,424	10/97	Saito et al. <i>Sup - on pg 1</i>			
LV	AI	4,528,066	7/85	Merkling, Jr. et al.			
	AJ	5,843,226	12/98	Zhao et al.			
	AK	6,093,655	7/00	Donoboe et al.			
LV	AL	09/080,656		Thomas Earl Allen III <i>now US# 6,235,213</i> STB/1998			

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
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	AO							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

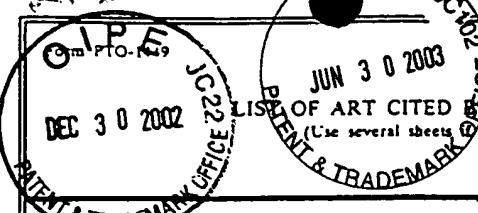
LAN VINH

DATE CONSIDERED

7/14/2003

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U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
LV	AA	09/429,380	10/99	Donoboe et al.			10/29/99	
LV	AB	5,935,340	8/99	Xia et al.				
	AC							
	AD							
	AE							
	AF							
	AG							
	AH							
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	AJ							
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FOREIGN PATENT DOCUMENTS								
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